

Application/Control	No.
10/561,364	

Examiner Lee Y Quach Applicant(s)/Patent under Reexamination
LAENEN ET AL.

Art Unit 2875

		ORIGINAL		INTERNATIONAL CLASSIFICATION											
	CLASS SUBCLA					LASS CLAIMED						NON-CLAIMED			
362				269		21	V	21	/30	F	21	v	21	/02	
	CROS	S REFEREI	ICES												
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362	275	419							1					1	
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 (Adei	Sant Exam	iner) (D	ate)	- Frank	w		<u> </u>	30/06	!	Total	Clain	ns Allo	owed: 1	2	
	Struments E	- 10	1- 181	QUACH-LEE ^{09/30/06} YEXAMINER (Date)					O.G. Print Claim(s)				O.G. Print F		

Claims renumbered in the same order as presented by applicant											□СРА			☐ T.D.			☐ R.1.47		
Final	Original		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original
	1			31			61			91			121			151			181
	2			32			62			92			122			152			182
	3			33			63]		93			123			153			183
	4			34			64			94			124			154			184
	5			35			65			95			125			155			185
	6			36			66			96			126			156			186
	7			37			67			97			127			157			187
4	8			38			68]		98			128			158			188
5	9	·		39			69]		99			129			159			189
1	10			40			70			100			130			160			190
2	11			41			71			101			131			161			191
3	12	İ		42			72	1		102			132			162			192
6	13			43			73	1		103			133			163			193
7	14	1		44			74]		104			134			164			194
8	15	1		45			75	1		105			135			165			195
9	16	1		46			76	1		106			136			166			196
10	17	1		47			77	1		107			137			167]		197
11	18	1		48			78	1		108			138	:		168			198
12	19	1		49			79	1		109	1		139			169			199
	20	1		50			80	1		110]		140			170			200
	21			51	1		81			111	1		141			171			201
	22			52]		82			112			142			172			202
	23	1		53	1		83			113]		143			173			203
	24	1		54	1		84	7		114	}		144			174			204
	25	1		55	1		85]		115]		145]		175]		205
	26	1		56	1		86			116			146]		176			206
	27	1		57	1		87			117			147			177			207
	28	1		58	1		88			118	1		148]		178]		208
	29			59	1		89	1		119	1		149]		179			209
	30]		60			90			120			150			180			210